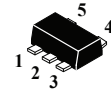


### Quad Array for ESD Protection

 Lead(Pb)-Free

This quad monolithic silicon voltage suppressor is designed for applications requiring transient overvoltage protection capability. It is intended for use in voltage and ESD sensitive equipment such as computers, printers, business machines, communication systems, medical equipment, and other applications. Its quad junction common anode design protects four separate lines using only one package. These devices are ideal for situations where board space is at a premium.

**Peak Pulse Power**  
100 Watts  
**Reverse Working Voltage**  
6.8VOLTS



**SOT-553**

#### Features:

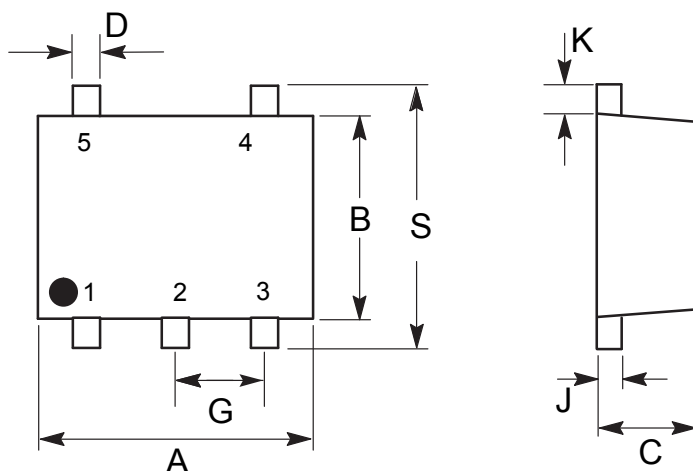
- \* SOT-553 Package Allows Four Separate Unidirectional Configurations
- \* Low Leakage < 1 $\mu$ A @ 3 Volt
- \* Breakdown Voltage: 6.8 Volt @ 1 mA
- \* ESD Protection Meeting IEC61000-4-2 - Level 4

#### Mechanical Characteristics:

- \* Void Free, Transfer-Molded, Thermosetting Plastic Case
- \* Corrosion Resistant Finish, Easily Solderable
- \* Package Designed for Optimal Automated Board Assembly
- \* Small Package Size for High Density Applications

### SOT-553 Outline Dimensions

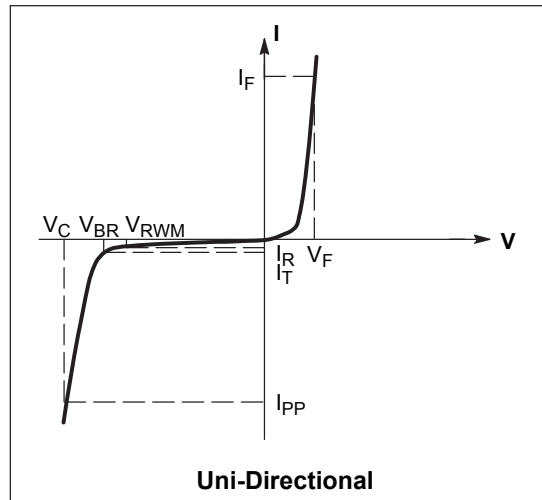
Unit:mm



SOT-553		
Dim	Min	Max
A	1.50	1.70
B	1.10	1.30
C	0.50	0.60
D	0.17	0.27
G	0.50 REF	
J	0.08	0.16
K	0.10	0.30
S	1.50	1.70

## ELECTRICAL CHARACTERISTICS (TA = 25°C unless otherwise noted)

Symbol	Parameter
$I_{PP}$	Maximum Reverse Peak Pulse Current
$V_C$	Clamping Voltage @ $I_{PP}$
$V_{RWM}$	Working Peak Reverse Voltage
$I_R$	Maximum Reverse Leakage Current @ $V_{RWM}$
$V_{BR}$	Breakdown Voltage @ $I_T$
$I_T$	Test Current
$V_{BR}$	Maximum Temperature Coefficient of $V_{BR}$
$I_F$	Forward Current
$V_F$	Forward Voltage @ $I_F$
$Z_{ZT}$	Maximum Zener Impedance @ $I_{ZT}$
$I_{ZK}$	Reverse Current
$Z_{ZK}$	Maximum Zener Impedance @ $I_{ZK}$



## MAXIMUM RATINGS (TA = 25°C unless otherwise noted)

Characteristic	Symbol	Value	Unit
Peak Power Dissipation (8 X 20 $\mu$ s @ TA = 25°C) (Note 1)	$P_{PK}$	100	W
Steady State Power - 1 Diode (Note 2)	$P_D$	300	mW
Thermal Resistance Junction to Ambient Above 25°C, Derate	$R_{\theta JA}$	370 2.7	°C/W mW/°C
Maximum Junction Temperature	$T_{Jmax}$	150	°C
Operating Junction and Storage Temperature Range	$T_J$ $T_{stg}$	-55 to +150	°C
ESD Discharge MIL STD 883C - Method 3015-6 IEC1000-4-2, Air Discharge IEC1000-4-2, Contact Discharge	$V_{PP}$	16 16 9	kV
Lead Solder Temperature (10 seconds duration)	$T_L$	260	°C

## ELECTRICAL CHARACTERISTICS (TA = 25°C)

Device	Breakdown Voltage $V_{BR}$ @ 1 mA (Volts)			Leakage Current $I_{RM}$ @ $V_{RM}$		$V_C$ Max @ $I_{PP}$		Typ Capacitance @ 0 V Bias (Note 3)	Max $V_F$ @ $I_F = 200$ mA
	Min	Nom	Max	$V_{RWM}$	$I_{RWM}$ ( $\mu$ A)	$V_C$ (V)	$I_{PP}$ (A)	(pF)	(V)
ESDA5V6V5	5.32	5.6	5.88	3.0	1.0	10.5	10	90	1.3
ESDA6V2V5	5.89	6.2	6.51	4.0	0.5	11.5	9.0	80	1.3
ESDA6V8V5	6.46	6.8	7.14	4.3	0.1	12.5	8.0	70	1.3

1. Non-repetitive current per Figure 1.
2. Only 1 diode under power. For all 4 diodes under power,  $P_D$  will be 25%. Mounted on FR-4 board with min pad.
3. Capacitance of one diode at  $f = 1$  MHz,  $V_R = 0$  V,  $T_A = 25^\circ$  C

## Device Marking

Item	Marking	Equivalent Circuit diagram
ESDA5V6V5		
ESDA6V2V5		
ESDA6V8V5	VE	

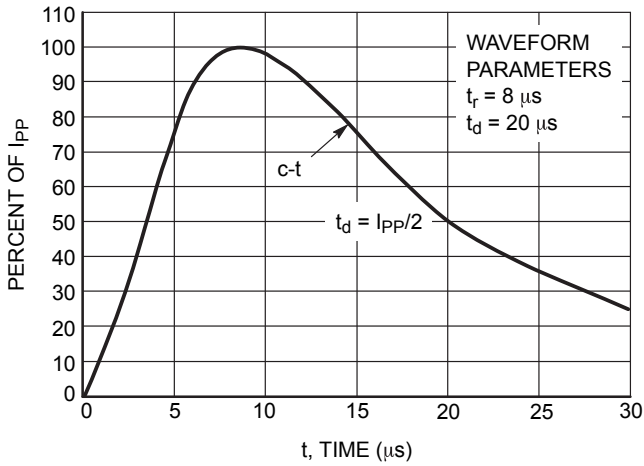


Figure 1. Pulse Waveform

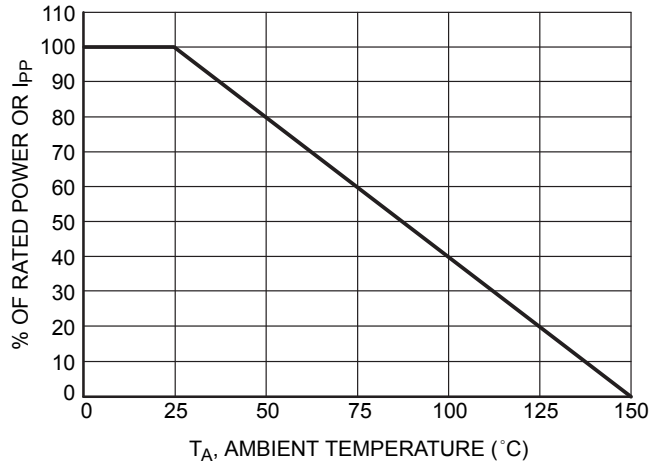


Figure 2. Power Derating Curve

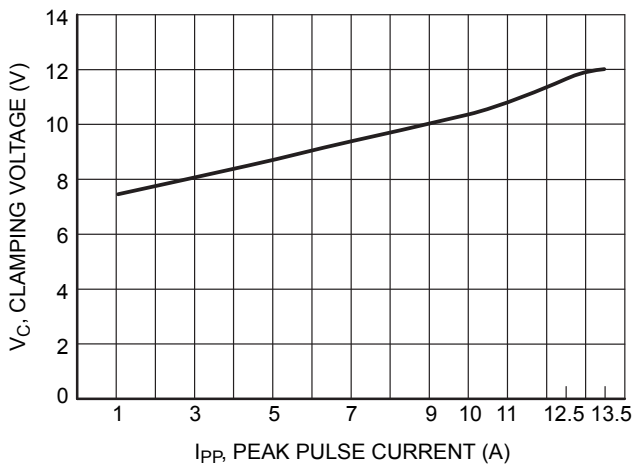


Figure 3. Clamping Voltage versus Peak Pulse Current

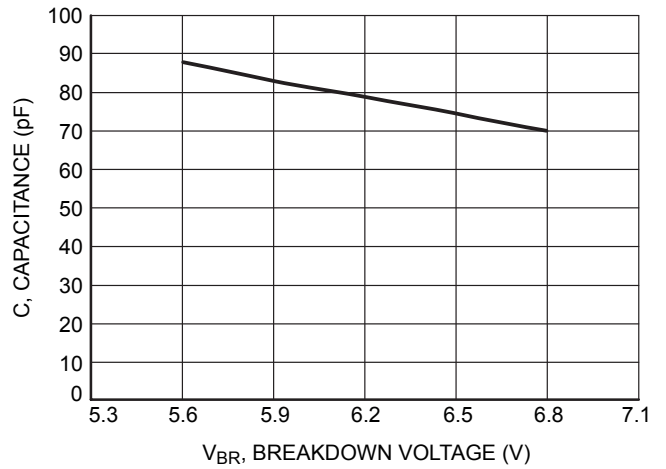


Figure 4. Typical Capacitance